Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,058	DELINE, JONATHAN
Examiner	Art Unit
Khai M. Nguyen	2617

SEARCHED			
Class	Subclass	Date	Examiner
see	previous		KN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEARC	H STRATEG	Y)
	DATE	EXMR
see previous		KN
·		
^		
	-	